

Search Notes**Application/Control No.**

10/808,818

Examiner

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Applicant(s)/Patent under Reexamination

JEON ET AL.

Art Unit

1722

SEARCHED

Class	Subclass	Date	Examiner
425	190	1/7/2006	EL
425	191	1/7/2006	EL
425	208	1/7/2006	EL
425	209	1/7/2006	EL
425	558	1/7/2006	EL
366	76.3	1/7/2006	EL
366	79	1/7/2006	EL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search	1/7/2006	EL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
<i>see EAST text search</i>	<i>1/7/2006</i>	<i>EC</i>	